

<b>Notice of References Cited</b>	Application/Control No. 10/605,811	Applicant(s)/Patent Under Reexamination HAYASHI ET AL.	
	Examiner Eric B. Compton	Art Unit 3726	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,524,728	06-1996	Williams et al.	184/29
*	B	US-5,862,841	01-1999	Wuester, Sr., David	141/284
*	C	US-2003/0221317	12-2003	Kaimi et al.	29/898.02
*	D	US-6,733,180	05-2004	Nakamura, Junichi	384/100
*	E	US-2004/0256178	12-2004	Neumann et al.	184/007.4
*	F	US-2005/0000092	01-2005	Misu et al.	029/898.02
*	G	US-2005/0095159	05-2005	Sumi et al.	418/001
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	08-270653	10-1996	JP	NIPPON	
	O	2002-05170	01-2002	JP	VICTOR	
	P	2002-168394	06-2002	JP	SEIKO	
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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